

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/580,648	TANAKA ET AL.	
Examiner		Art Unit		Page 1 of 1
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 2002-347107	04-2002	Japan	Shimomura et al	
	O					
	P					
	Q					
	R					
	S					
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**NON-PATENT DOCUMENTS**

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